Search Notes	

Application/Control No.	Applicant(s)/Patent Reexamination	under
09/750,489	YAUNG, ALAN T.	
Examiner	Art Unit	
VAN H. NGUYEN	2194	

	SEAR	CHED	
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INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH I (INCLUDING SEAR)
	DATE	EXMR
WEST UPDATED	5/14/2006	VN
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